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San Juan | Puerto Rico

ELECTIONS at ARFTG-104

ARFTG Executive Committee Candidates 2024



Joel Dunsmore (Keysight Technologies, USA) is a Keysight R&D Fellow working at the Santa Rosa Site. He received his Ph.D. from Leeds University in 2004. He was a principal contributor to PNA family of network analyzers, with recent work in non-linear test, including differential devices, and mixer measurements, as well as modulated and spectrum measurements. He has received 36 patents and authored the “Handbook of Microwave Component Measurements, 2nd Edition (John Wiley, 2020)”, and has the YouTube Channel @DrJoelVNA. He has been a member of ARFTG ExCom for 6 years, has been general chair of one ARFTG conference and Technical Program Chair of another, and is the ongoing ARFTG Conference Exhibits

Chairperson.



Dennis Lewis (Boeing, USA) received his BS EE degree with honors from Henry Cogswell College and his MS degree in Physics from the University of Washington. He has worked at Boeing for 35 years and is recognized as a Technical Fellow, leading the enterprise antenna measurement capability for Boeing Test and Evaluation. Dennis holds twelve patents and is the recipient of the 2013 & 2015 Boeing Special Invention Award. He is a senior member of the IEEE and several of its technical societies including the Microwave Theory and Techniques Society (MTT-S), the Antennas and Propagation Society and the Electromagnetic Compatibility (EMC) Society. He actively contributes to these societies as a member of the

IEEE MTT-S subcommittee 3 on microwave measurements and as a Board Member and a past Distinguished Lecturer for the EMC Society. He is a Senior Member and served as Vice President on the Board of Directors for the Antenna Measurements Techniques Association (AMTA) and chaired its annual symposium in 2012 & 2023. As a past faculty member at North Seattle College, Dennis developed and taught a course on The Fundamentals of Measurement Science. He is also a past chair and serves on the Technical Advisory Committee. His current technical interests include aerospace applications of reverberation chamber test techniques as well as microwave and antenna measurement systems and uncertainties.



Patrick Roblin (The Ohio State University (OSU), USA) received the Maîtrise de Physics degree from the Louis Pasteur University, Strasbourg, France, in 1980, and the M.S. and D.Sc. degrees in electrical engineering from Washington University, St. Louis, MO, in 1982 and 1984, respectively. In 1984, he joined the Department of Electrical Engineering, at the Ohio State University (OSU), Columbus, OH, where is currently a professor. At OSU, he developed two educational RF/microwave laboratories and associated curriculum and founded the Non-Linear RF research lab. His research interests include the measurement, modeling, design and linearization of non-linear RF devices and circuits. He authored and co-authored three

textbooks: two with Cambridge University Press and one with Springer. From 2016 to 2018 he served as Distinguished Microwave Lecturer for IEEE-MTT. He is currently serving as vice-president of ARFTG and as co-chair of the MTT Technical Committee TC3 on Microwave Measurements.



Xiaobang Shang (Senior Member, IEEE, National Physical Laboratory (NPL), UK) received his BEng (First Class) in Electronic and Communication Engineering in 2008 and his PhD in Microwave Engineering in 2011 from the University of Birmingham, UK. In 2017 he joined the National Physical Laboratory (NPL, UK) as a Senior Scientist, and was promoted to a Principal Scientist in 2023. His current research interests are on-wafer measurements (at room temperature and cryogenic temperatures), material characterizations, calibration, and de-embedding. Dr. Shang was the Coordinator for EMPIR TEMMT project (2019 – 2022), a large-scale European Union metrology project involving 19 partners globally. He has authored or

co-authored over 120 articles on microwave measurements and microwave circuits. He is a member of IEEE MTT-S TC-3 and TC-21, an Associate Editor for IEEE Microwave and Wireless Technology Letters (2020-2024), and a Visiting Professor at the University of Manchester. He represents Group 4 countries on the EuMA General Assembly (2022–2024) and is selected by EuMA as the General TPC Chair for EuMW 2026. Dr. Shang was the recipient of several prestigious awards including the IEEE MTT-S Outstanding Young Engineer Award in 2025, the Roberto Sorrentino Prize in 2022, the IEEE MTT-S Tatsuo Itoh Award in 2017, and the ARFTG Roger Pollard Microwave Measurement Student Fellowship in 2009. He looks forward to volunteering for the ARFTG community and contributing to its activities.



Dominique Schreurs (KU Leuven, Belgium) has been involved with ARFTG since the previous millennium. She attended her first ARFTG conference as a PhD student in 1996, and has attended most ARFTG conferences since, resulting in receiving the ARFTG Life Member status in 2013. She organized the very first workshop at a Fall ARFTG Symposium in 2001 and has been (co)organiser and speaker in various ARFTG workshops over the years. She was one of the co-initiators of the NVNA Users' Forum in 2002 and is still acting as its advisor. Dominique got elected to the ARFTG Executive Committee in 2003 and has assumed various ExCom positions over the years (Workshop Chair, Education Chair, Technical Coordination, Secretary,

Nominations, Awards, MTT-S Liaison, ...), including ARFTG President in 2018-2019. Dominique is acting frequently as a reviewer on the ARFTG TPC, and was TPC chair of 2002 Fall ARFTG, 2016 Spring ARFTG, and 2023 Winter ARFTG. She was General Chair of the Spring ARFTG conferences in 2007, 2012, 2018, and 2024. She was also an instructor at the ARFTG Short Course numerous times. In daily life, Dominique is a full professor at KU Leuven in Belgium. Belgium is the birthplace of the early NVNA prototypes (called LSNA at the time), and therefore it is natural that her research embarked on nonlinear microwave measurements. In recent years, her students have been working on topics such as experiment design, measurement uncertainty, measurement-based modelling of devices, dielectric spectroscopy measurements, MIMO antenna characterisation,... to name a few. Her research is documented in about 900 publications (books, journal papers, and conference contributions), among which a substantial number were presented at ARFTG conferences. When Dominique was a post-doc, she performed scientific stays at Agilent Technologies (now Keysight Technologies) in Santa Rosa, CA, and NIST in Boulder, CO. As a professor, she performed a sabbatical at NIST and also has been sending her PhD students over there. Dominique is highly motivated to continue serving the ARFTG community. As ARFTG Past President and ARFTG Life Member, she can leverage on her longstanding experience in her future contributions on ExCom.



Andrej Rumiantsev (MPI Corporation, Taiwan) received his Diploma-Engineer degree (with highest honors) in Telecommunication Systems from the Belarusian State University of Informatics and Radioelectronics (BSUIR) in Minsk, Belarus, in 1994, and his Dr.-Ing. degree (summa cum laude) in Electrical Engineering from Brandenburg University of Technology (BTU) Cottbus, Germany, in 2014. Since 2001, he has worked in engineering, product management, and marketing for leading companies in RF technologies, contributing to innovations in RF wafer probes, calibration standards, software, and probe systems. He is currently the Director of RF Technologies at MPI Corporation. Dr. Rumiantsev actively contributes to the field as a member

of the IEEE MTT-3 Microwave Measurements Committee, Chair of the IEEE MTT-S P2822 Working Group, and ExCom member of ARFTG. He holds multiple patents in wafer-level RF calibration and measurement techniques, and his doctoral thesis received the "Best Dissertation of 2014" award at BTU.

Why I'm Running for Re-Election. My journey with ARFTG started 20 years ago, at ARFTG-63, where I published my first ARFTG paper. Since then, ARFTG has become an irreplaceable part of my professional career, both as a conference and as a community. I had the honor of being part of the organizing committee for the ARFTG On-Wafer Users' Forum, which we launched at ARFTG-88. Over the years, this forum has grown into an integral part of the ARFTG community, fostering valuable discussions and advancements in wafer-level measurements. At the upcoming ARFTG-104th Symposium, we will celebrate the 20th On-Wafer Users' Forum—a milestone that highlights the forum's impact and longevity. I have contributed to organizing multiple ARFTG conferences and symposia, serving several times as General Chair and Technical Program Chair. I also played a key role in recent rebranding ARFTG and creating the new look and feel of our documents and website, which I currently manage. In recognition of my long-term service, I was granted ARFTG Life Member status, an honor that reinforces my commitment to this community. If re-elected, I'll continue working to expand ARFTG's impact, and I'm excited about what we can achieve together to keep ARFTG at the forefront of our field.



James Skinner (National Physical Laboratory (NPL), UK) is a microwave metrologist at the UK's National Physical Laboratory (NPL). His expertise is in VNA calibration and S-parameter metrology for coaxial and waveguide media. In his role at NPL, he has been responsible for maintaining the UK primary standards for RF impedance since 2016. Since 2020, he has authored and co-authored over 30 scientific publications on metrology research from kHz to THz frequencies, covering topics including sub-THz waveguides, cryogenic measurements for quantum computing, time-domain metrology, on-wafer measurements and novel calibration technologies. He was awarded a first class Masters degree in Electronic

Engineering from Queen Mary University London in 2016, and is currently studying a PhD in Microwave Engineering at Imperial College London. He currently serves as secretary for the IEEE P1785 working group for waveguide standards above 110 GHz, and is looking to bring his passion and enthusiasm for metrology to the role of ARFTG ExCom member.